

**Search Notes**

Application/Control No.

09/590,173

Examiner

Madeleine AV Nguyen

Applicant(s)/Patent under  
Reexamination

FUJITA, KATSUSHI

Art Unit

2626

**SEARCHED**

Class	Subclass	Date	Examiner
update		8/28/2005	AV
358	1.9		
	529		
	509		
	514		
358	530		
355	32		
355	37		
347	115		
	118		
	232		
	238		
	240		
347	251	8/28/2005	AV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/28/2005	AV
Interference search, History Printout	8/28/2005	AV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
358	1.9	8/28/2005	AV
358	509	8/28/2005	AV

**Search Notes (continued)**

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**SEARCHED**

Class	Subclass	Date	Examiner
430	293	9/28/2005	AV
	138		
	505		
430	358		
382	167		
382	162	9/28/2005	AV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner